

A comparison between Ex-DPD_{FE} and other feature-based methods

Characteristics Reference	Structural	Behavioral		Pattern-independent	Distinction ability	Variants detection	Accuracy	Time-efficiency	Language-independence	Complete automation
		Static	Dynamic							
Ex-DPD _{FE}	✓	✓	×	✓	✓	✓	✓	✓	✓	✓
[50]	✓	×	×	×	✓	×	✓	✓	✓	×
[52]	✓	✓	×	×	✓	×	×	-	×	✓
[53]	✓	×	×	×	×	×	×	✓	×	✓
[54]	✓	×	×	✓	✓	×	×	×	✓	✓
[55]	✓	×	×	✓	✓	×	×	×	✓	✓
[56]	✓	×	×	✓	✓	×	✓	-	✓	✓
[57]	✓	×	×	✓	✓	×	✓	-	×	✓
[61]	✓	✓	×	×	×	×	×	✓	✓	✓
[62]	✓	×	×	✓	✓	✓	-	✓	✓	×
[63]	✓	×	×	×	×	×	-	✓	✓	×
[64]	✓	×	×	×	×	✓	×	✓	✓	✓
[65]	✓	×	×	✓	✓	×	✓	-	×	✓
[58]	✓	✓	×	×	×	×	×	✓	✓	✓
[59]	✓	×	×	✓	✓	×	✓	-	×	✓
[60]	✓	×	×	✓	✓	×	✓	-	×	✓

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